Se	arch	Note	es	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/749,354	CHAN ET AL.
Examiner	Art Unit
Christopher D. Koharski	3763

SEARCHED			
Class	Subclass	Date	Examiner
604	246	2/27/2006	CDK
604	22	2/27/2006	CDK
604	41	2/27/2006	CDK
604	523	2/27/2006	CDK
604	533	2/27/2006	CDK
604	164.1	2/27/2006	CDK
604	96.01	2/27/2006	CDK
604	264	2/27/2006	CDK
604	158	2/27/2006	CDK
604	164.13	2/27/2006	CDK
604	164.01	2/27/2006	CDK
604	164.03	2/27/2006	CDK
604	85	2/27/2006	CDK

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
			<u> </u>

SEARCH N (INCLUDING SEARC)	
	DATE		
East Search	2/27/2006	CDK	
Inventor Search	2/27/2006	CDK	
PLUS Search	2/27/2006	CDK	
East Search Updated	7/13/2006	CDK	
East Search Updated	9/22/2006	CDK	
East Search Updated	11/19/2006	CDK	